Search Notes



Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/604,943	BENTWICH, ITZHAK	
Examiner	Art Unit	
Dana Shin	1635	

SEARCHED					
Class	Subclass	Date	Examiner		
702	002	10/23/2006	DS		
424	199.1	10/23/2006	DS		
	93.2	10/23/2006	DS		
435	6	10/23/2006	DS		
•					

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	(m)			
	·	·		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
STIC - SEQ ID NO:3760, results available on SCORE	10/1/2006	DS
PALM - inventor name search	10/23/2006	DS
EAST - serach strategy attached.	10/23/2006	DS